

# **Chap. 8: Design Methodology and Tools**

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# Outline

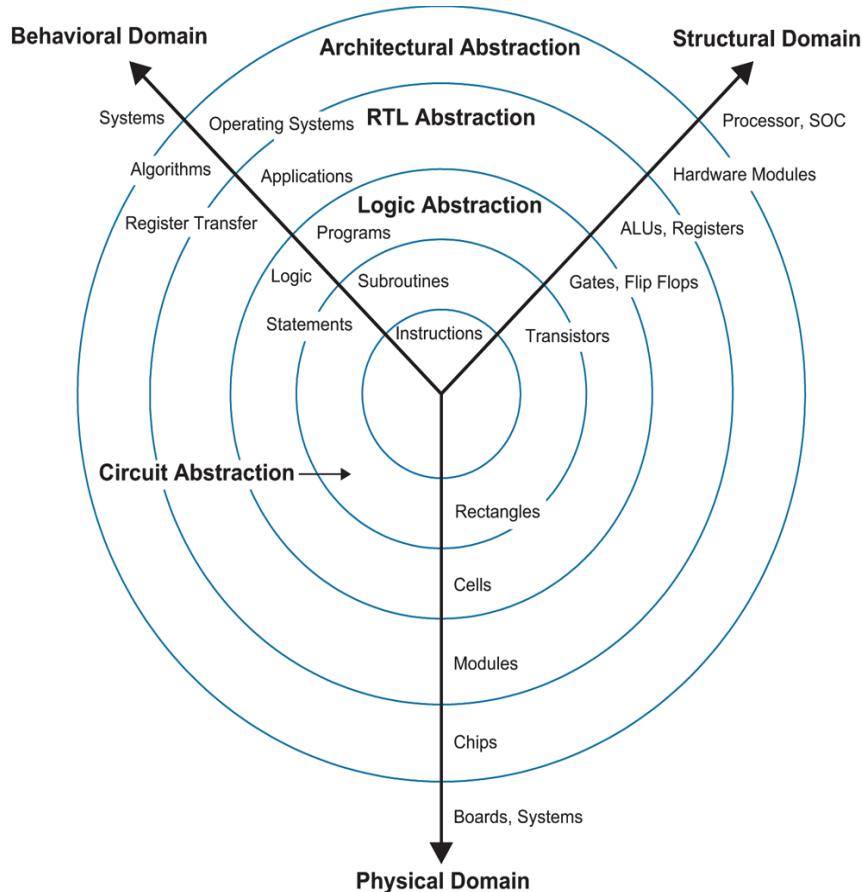
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- Design Domains: Y chart
- Structured Design Strategies
- Design Methods
- Design Flow
- Design Economics
- Data Sheets and Documentation
- Closing the Gap between ASIC and Custom
- CMOS Physical Design Styles
- Interchange Formats

# Why Design Methodology?

- **Design method gives impact on both effort and outcome of the design**
  - Borrows concept from multiple disciplines such as SW engineering
  - Broad principles: not changed
  - Details: evolved, need to monitor corresponding tools and literatures
- **Three domains**
  - Behavioral
    - **What to do:** ultra low-power radio for sensor network, wireless standard
  - Structural
    - **Interconnect of components:** connection between sensor, transceiver, up, memory,..., logic family, clocking strategy
  - Physical
    - **How to arrange component:** PCB layouts, chip or boards

# Y Chart



- Each domain can be hierarchically divided into different levels of abstraction, typically
  - Architectural
  - RTL
  - Logic
  - Circuit
- need verification of correctness after transformation between domains

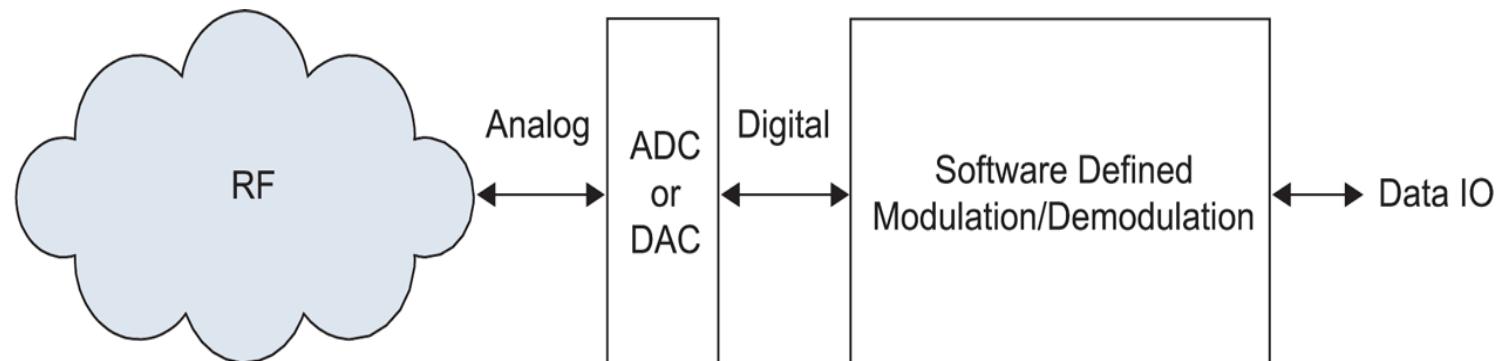
FIG 8.1 Gajski-Kuhn Y chart

# Structured Design

- Design is a continuous tradeoff for the following parameters to measure the goodness of VLSI system on the three domains
  - Performance: speed, power, function, flexibility
  - Size of die: cost
  - Time to design: cost
  - Ease of verification and test: cost
- Why the structured design?
  - For complex system design, the role of good VLSI design aids is to reduce this complexity and to increase productivity.
  - A good method of simplifying the approach is by the use of constraints and abstractions
    - Constraint: tool designer can automate the procedure
    - Abstraction: can collapse details and arrive at a simpler object to handle.

# Software Radio

- To explain the structured design, we take the abstract software radio as an example
  - Information is modulated onto RF carrier



**FIG 8.2** Software radio block diagram

# Software Radio Transmit Path

## □ Upconversion

- Intermediate frequency: 20Mhz
- RF
  - 2.402 or 2.398GHz, analog frequency multiplier: mixer

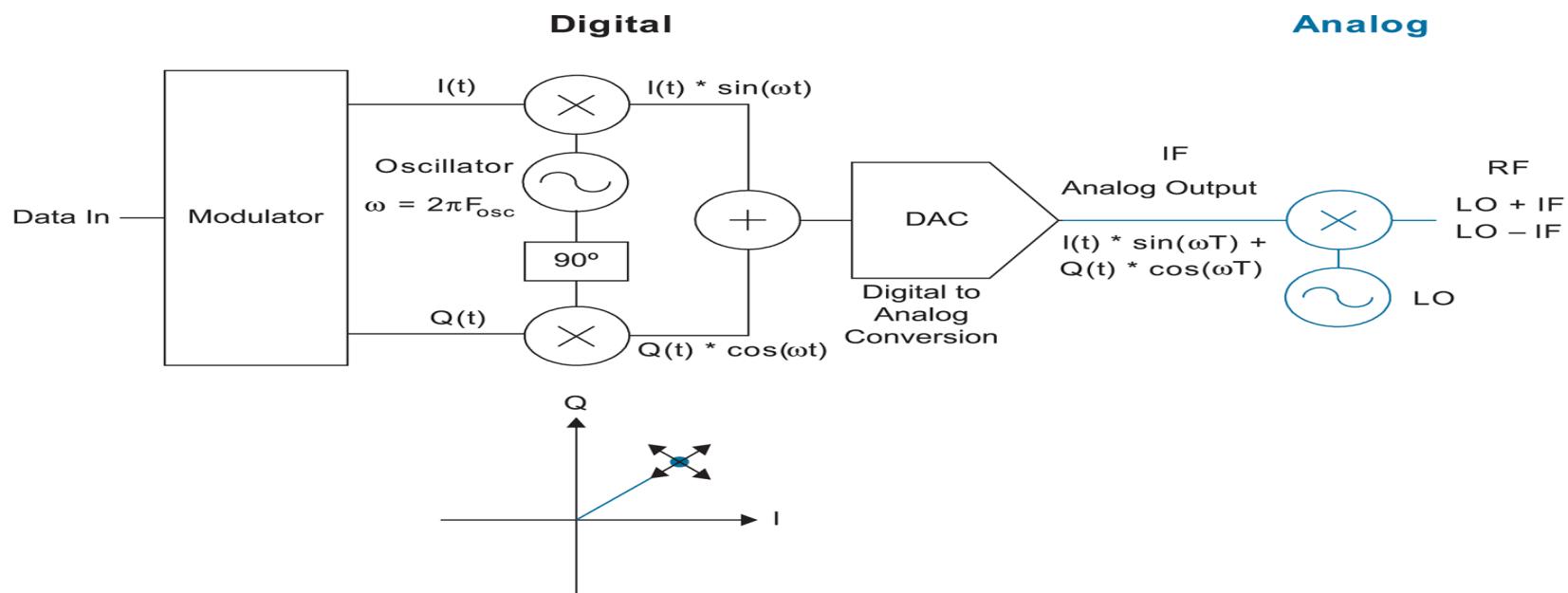
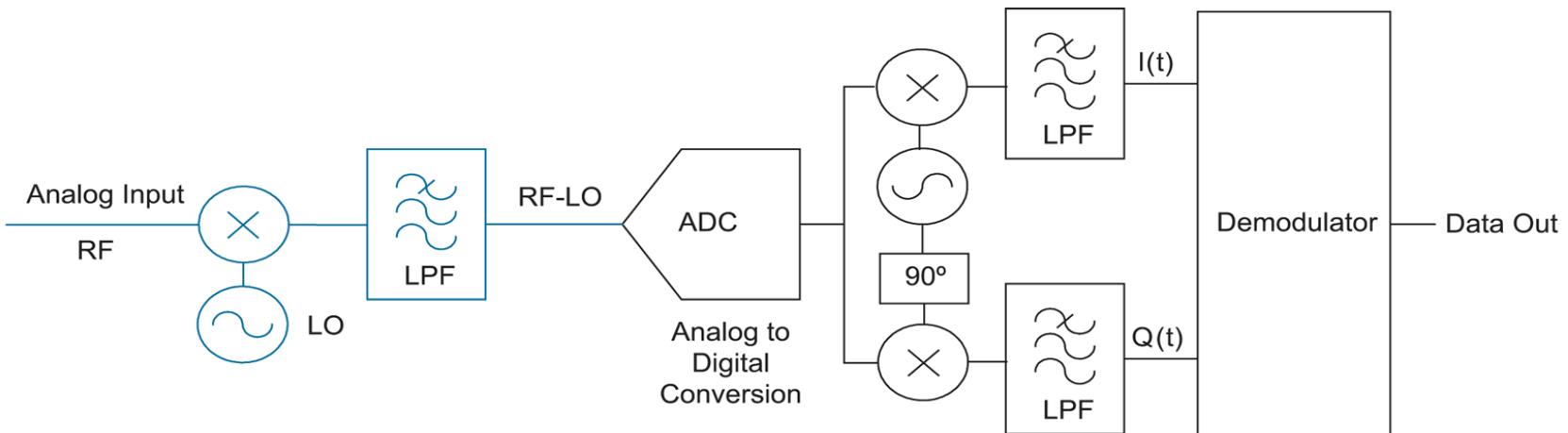


FIG 8.3 Software radio transmit path

# Software Radio Receive Path

- Downconversion

- 2.402 or 2.398GHz RF to 20Mhz IF for ADC



**FIG 8.5** Software radio receive path

- In summary, multiplication, sinewave generation, and filtering are important for SDR

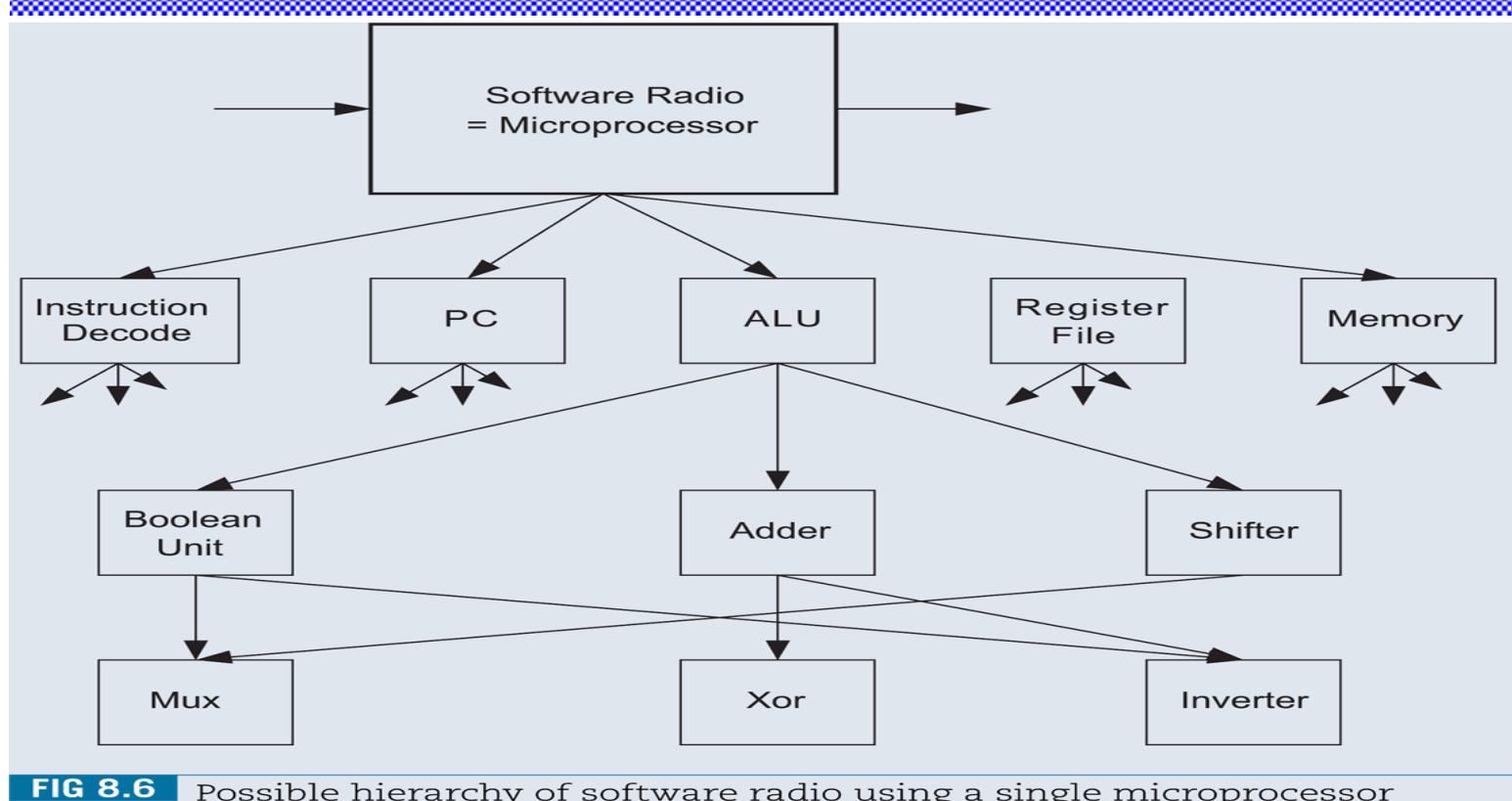
# Structured Design Strategies

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## □ Four guides

- Hierarchy
- Regularity
- Modularity
- Locality

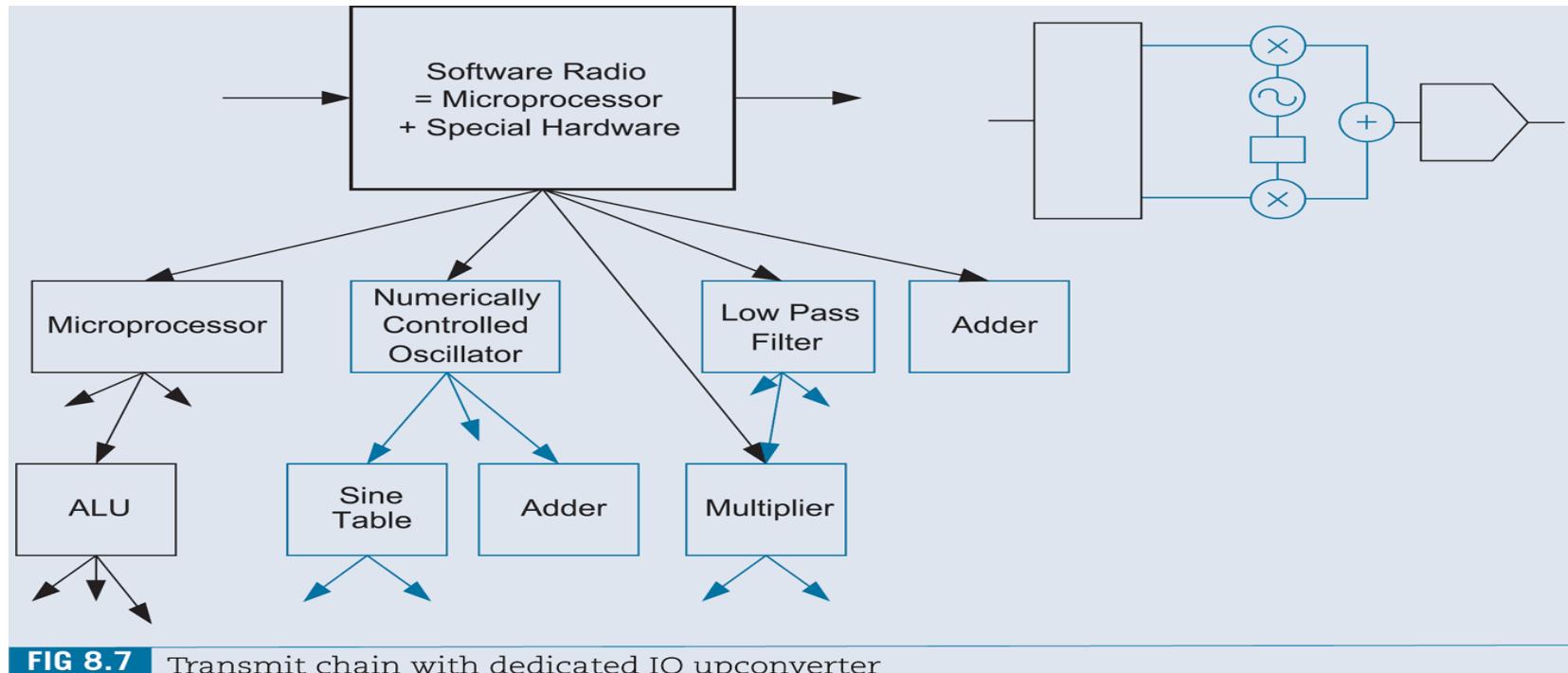
# Hierarchy: Example 1



**FIG 8.6** Possible hierarchy of software radio using a single microprocessor

- Software solution using a single processor

# Hierarchy: Example 2



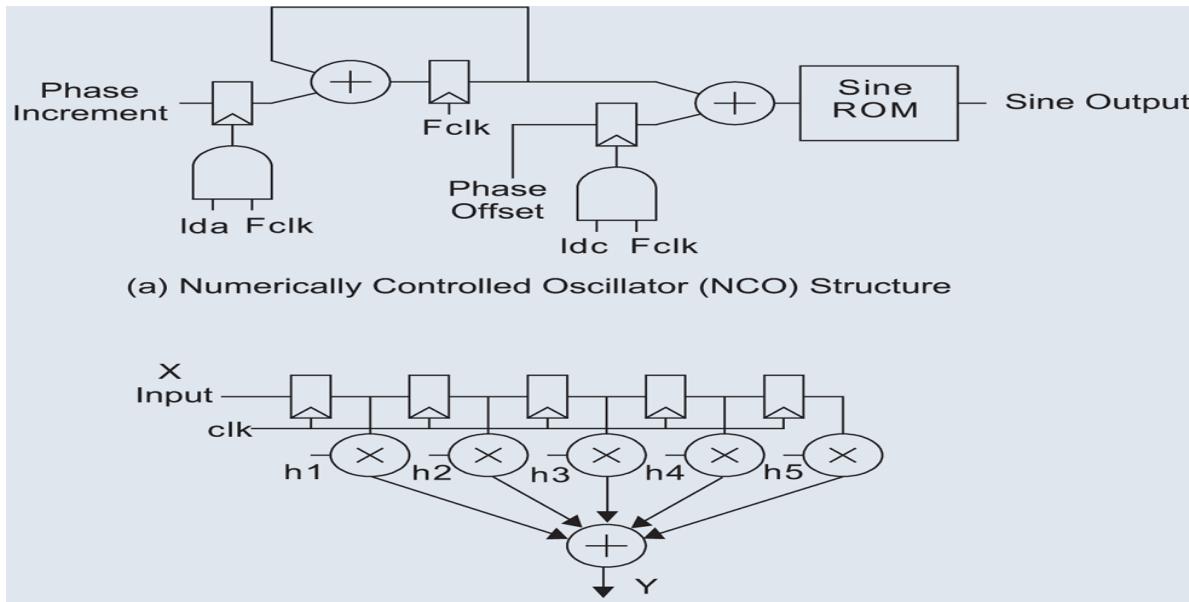
- Better solution to use dedicated HW for the computationally intensive fixed-function blocks

# Regularity

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- **Hierarchy alone does not solve the complexity problem**
  - May end up with a large number of different submodules → **still complex !!**
- **With regularity as a guide, the designer attempts to divide the design hierarchy into a set of similar building block**
  - Circuit level: same sized TRs
  - Gate level: finite library of fixed height
  - Logic level: RAMs and ROMs in multiple places
- **Regularity**
  - Design reuse!!
  - Aids in verification efforts

# Regularity: Example 1

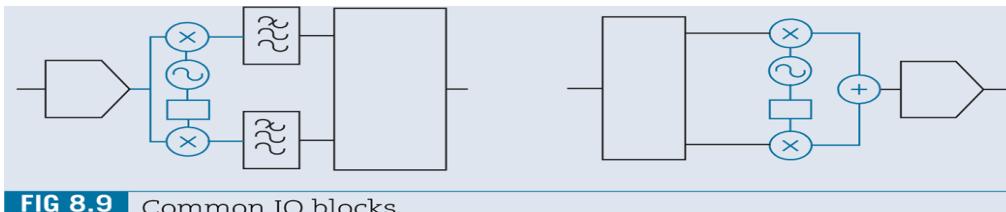


**FIG 8.8** Structure of numerically controlled oscillator and low-pass filter (implemented as a finite impulse response (FIR) filter)

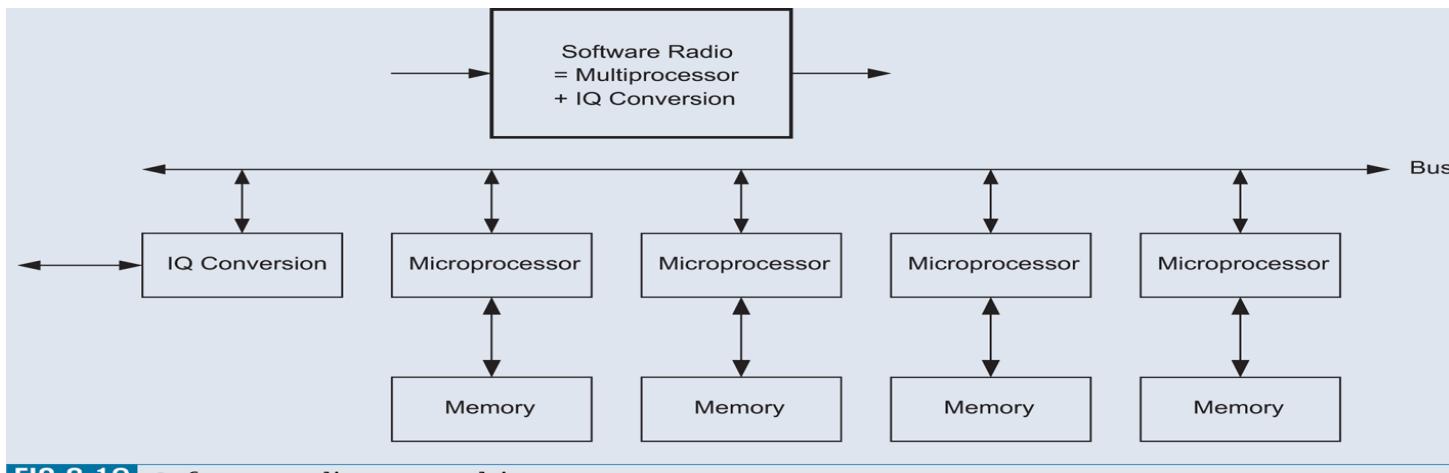
- **Common functions**
  - Register, adders and multipliers

# Regularity: Example 2

- IQ upconversion and downconversion: fixed hardware

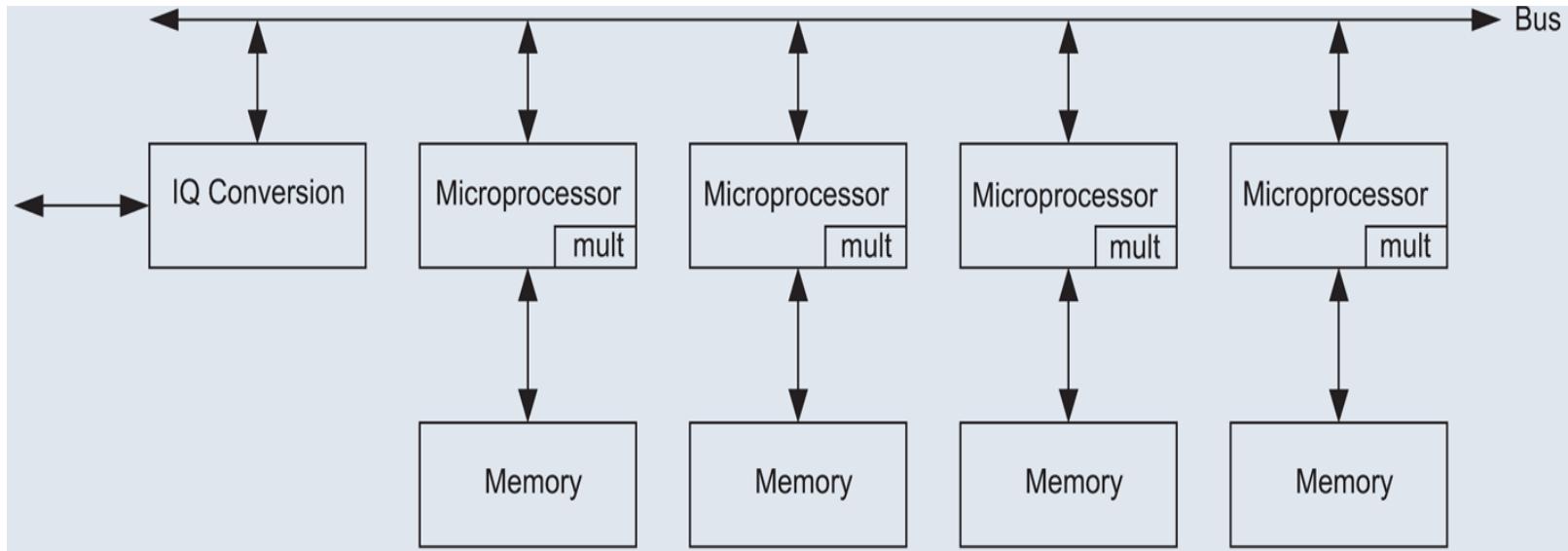


- Key feature of the software defined radio
  - Programmability!!



# Regularity: Example 2

- Enhanced up which embeds one-cycle mutiplication



**FIG 8.11** Enhanced multiprocessor for software radio

# Modularity

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- ❑ **Modularity states that “modules have well-defined functions and interfaces”**
- ❑ **“well-formed”?**
  - Clearly defined behavioral, structural, and physical interface that indicates functions
  - As well as name, signal type and electrical and timing constraints of the ports
- ❑ **Examples**
  - No too large fan-in or too small a drive capability
  - For noise immunity, inputs should only drive TR gates, not diffusion
  - Network on chip (NoC)

# Modularity: Example 1

- Which FF?

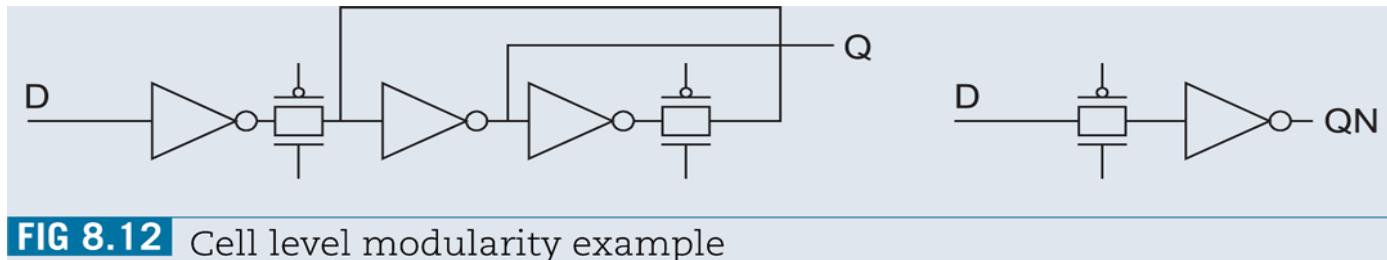


FIG 8.12 Cell level modularity example

- Another form of modularity: add testability for all register and register IO module for ease of input arrival time

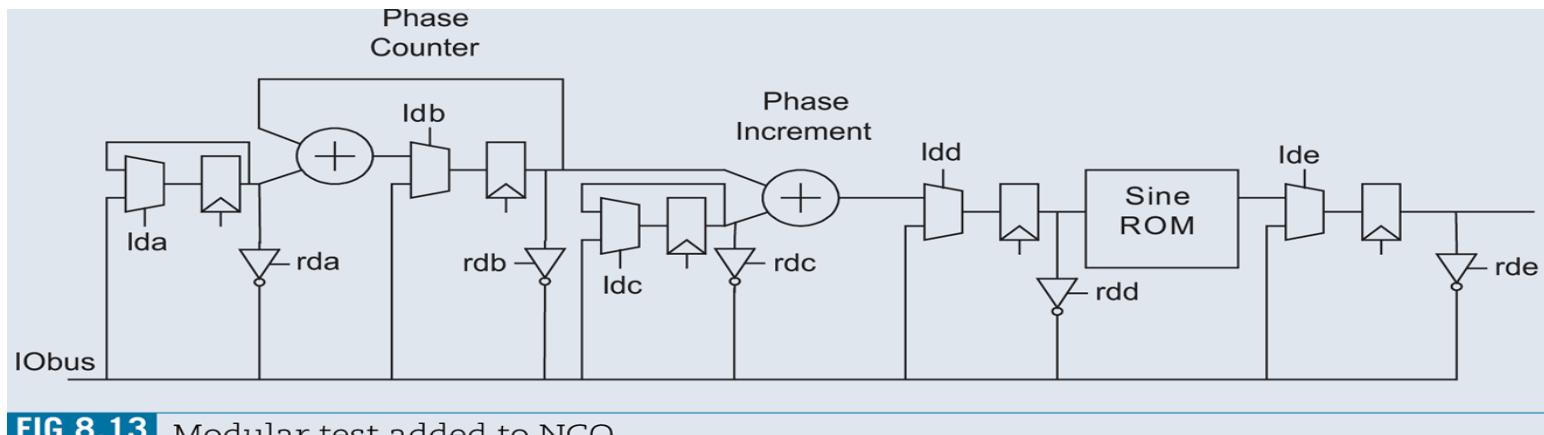
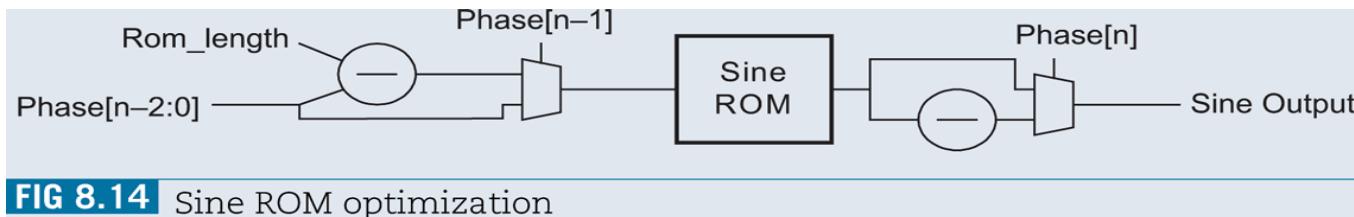


FIG 8.13 Modular test added to NCO

# Modularity: Example 2

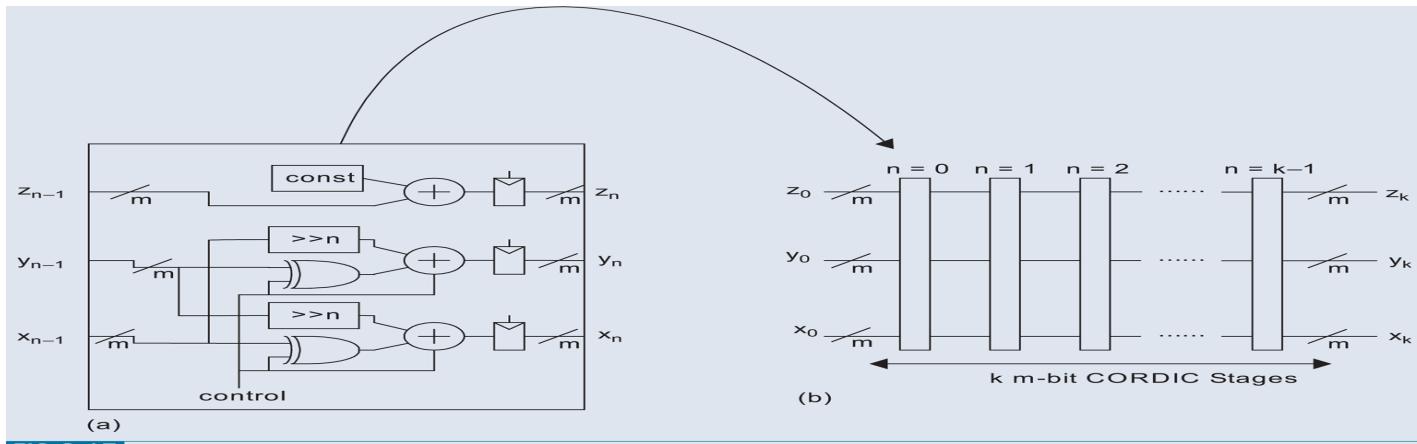
## □ Compact sine ROM

- Store only the first quadrant of the sine wave
- Good for small sine lookup table



**FIG 8.14** Sine ROM optimization

## □ Alternative structure: CORDIC



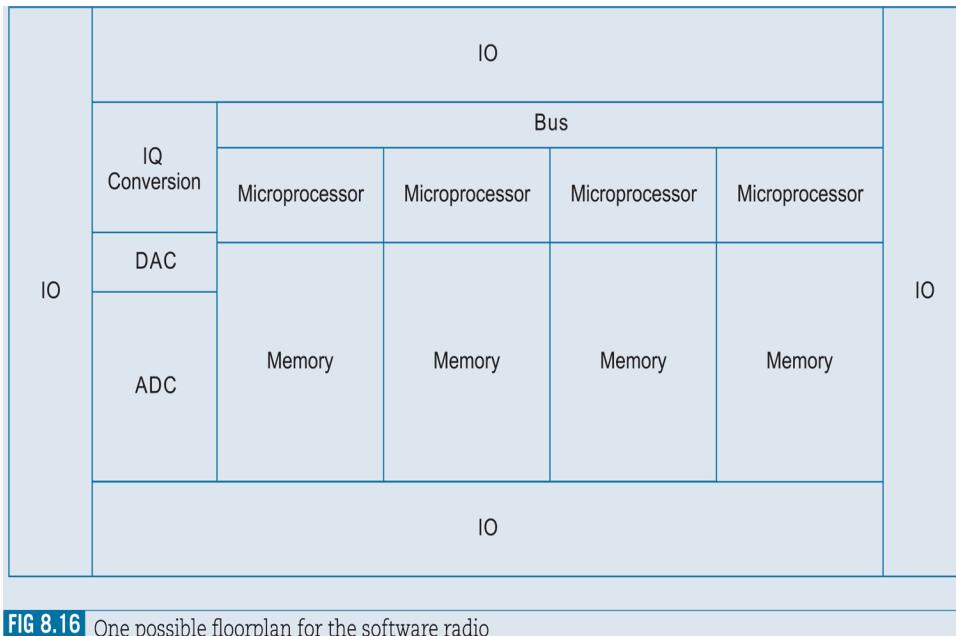
**FIG 8.15** CORDIC processor as a sine generator

# Locality

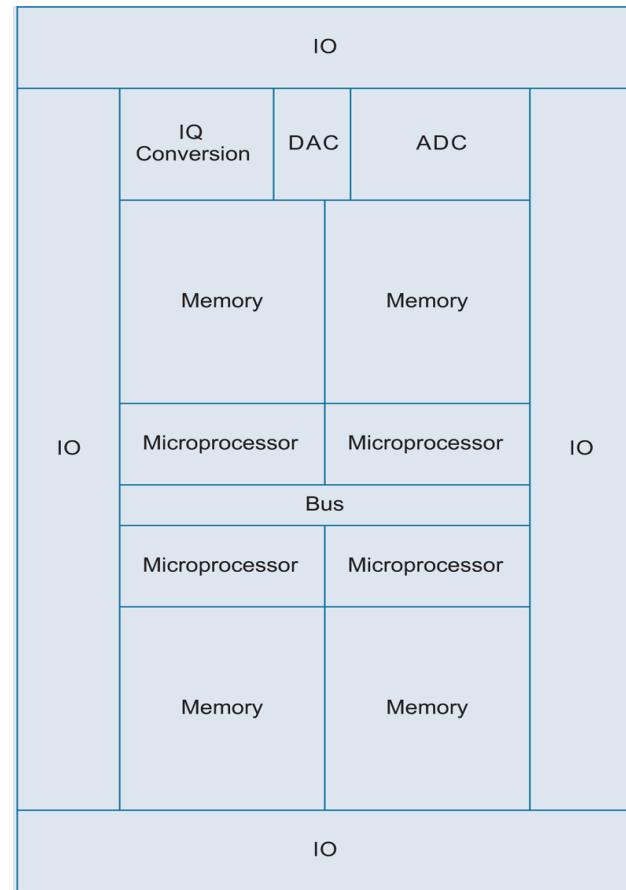
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- **Internals of the modules are unimportant to other module**
  - “Information hiding” to reduce complexity
  - Ex: reduce global variables
- **Physical (spatial) locality:** above example
- **Temporal locality**
  - Clock protocol: the three clocking strategies in Chap. 7.

# Locality: Examples



- **Floorplanning: Analog components close to IO pads**
  - Large DC current → short Power busses
- **Which one has better locality?**



# Structured Design: Summary

Design principle	Software	Hardware
Hierarchy	Subroutine, libraries	Modules
Regularity	Iteration, code sharing, object-oriented procedures	Datapaths, module reuse, regular arrays, gate arrays, standard cells
Modularity	Well-defined subroutine interfaces	Well-defined module interfaces, timing and loading data for modules, registered IOs
Locality	Local scoping, no global variables	Local connections through floorplaning

# Design Methods

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- With what method to implement a CMOS system?  
→ design method → implementation tech!
- Need to know the costs, capabilities, and limitations of a given implementation technology
  - Microprocessor/DSP
  - Programmable logic: PLA, FPGA
  - Gate Array and Sea of Gates
  - Cell-based
  - Full custom
  - Platform-based

# **Microprocessor/DSP**

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- Great flexibility: SW upgrade**
  - But SW development costs
- Embedded commercial processor**
  - ARM
  - MIPS
  - IBM's PowerPC
  - Sun SPARC V8

# Programmable logic: PLA

- Cost, speed, or power dissipation of uPs may not meet system goal
- More efficient alternative than uPs and yet faster to develop than ASIC
  - Chip with (re)programmable {logic arrays, interconnect}
- Programmable logic array (PLA)
  - Limited routing capability than FPGA
  - AND and OR planes

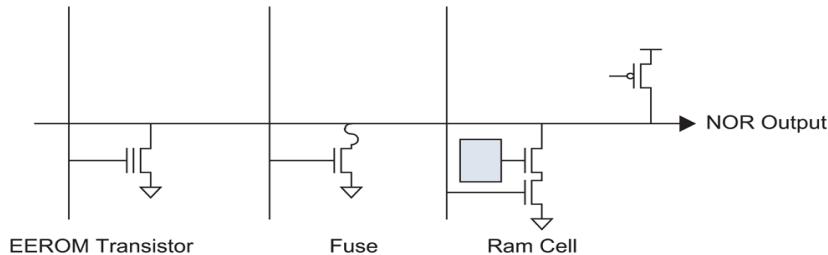


FIG 8.18 PLA NOR structure (one plane shown)

# Programmable logic: FPGA

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- **Field-programmable Gate Arrays**
  - Completely programmable even after shipped, or “in the field”
- **Programmability**
  - Actel: logic module (LM)
  - Xilinx: configurable logic block (CLB)
- **More advanced**
  - Add FFs, multipliers, ..., etc.

# Programmable Logic: FPGA

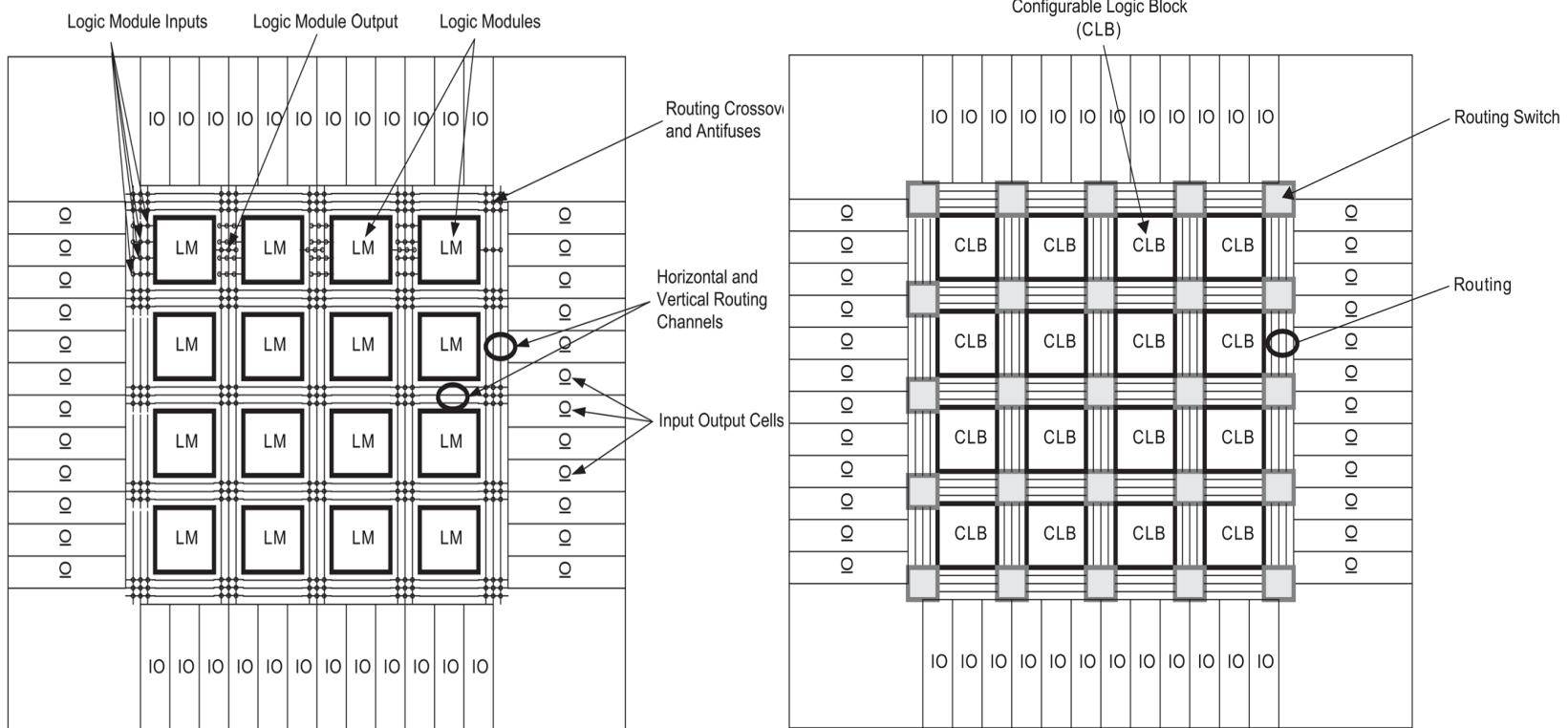


FIG 8.20 Representative Actel FPGA floorplan

FIG 8.21 Simplified FPGA floorplan

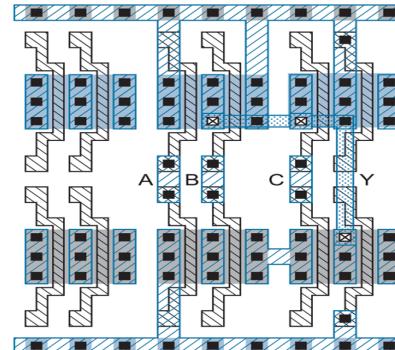
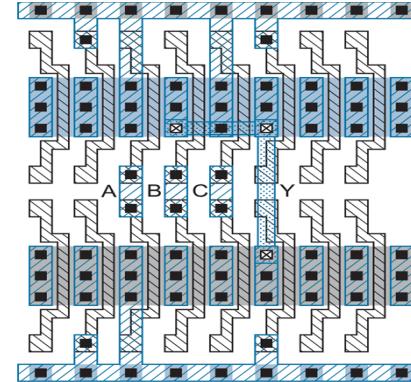
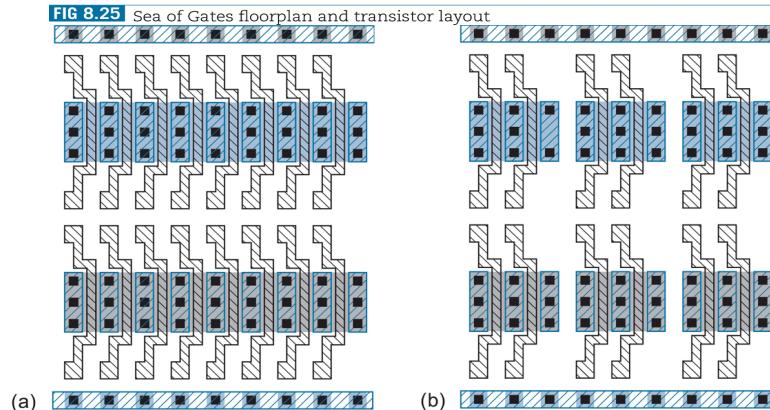
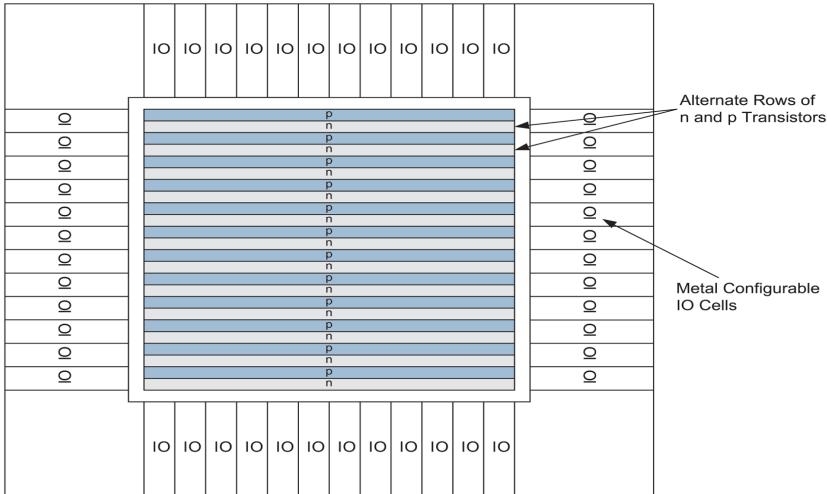
**See Fig. 8.22 for details of CLB!**

# Gate Array and Sea of Gates

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- To reduce nonrecurring engineering cost (NRE)
  - Construct common base array of TRs (vendor) and personalize the chip by altering the metalization (per design basis)
  - Gate array (GA)
  - Sea-of-gate (SoG) (subclass of GA)
  - LSI RapidChip technology
    - RISC core + 10Mbit RAM + I/O up to 4.25Gbps  
→ 300MHz

# Gate Array and Sea of Gates



# Cell-based Design

- **Use a standard cell library as the basic building blocks of a chip**
  - Smaller, faster, and lower-power chips than GA or FPGA
  - High NRE costs for custom mask set → only economical for high volume parts
  - Much higher productivity than full-custom design
- **Foundries and library vendors supply cells with a wide range of functionality**
  - SSI (NAND, NOR, XOR, AOI, OAI, inverters, buffers, registers)
  - MSI (adders, multipliers, parity blocks,...)
  - Memories (RAM, ROM, CAM, register files)
  - System level module (*u*Ps, interfaces, interfaces)
  - Possibility of mixed-signal and RF modules
  - See table 8.3, p 511

# Full-Custom Design

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- Oldest and most traditional techniques: *custom mask layout!!*
  - Polygon pushing: laborious and prone to error
  - Symbolic layout
    - Use primitives: TRs, contacts, wires, ports
- Analog and RF, cell libraries, memories and I/O cells still frequently use custom design
- Silicon complier: software generator to generate physical layout

# Platform-based

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- Increased system complexity → better to use predefined IP blocks
- Design frequently uses a number of common blocks
  - RISC, memory, I/Os attached to common busses
- Use *platform* by using common structures such as busses and common high level language to program the processor

# Design Methods: Summary

- See table 8.4 p. 519
- Design decision tradeoff

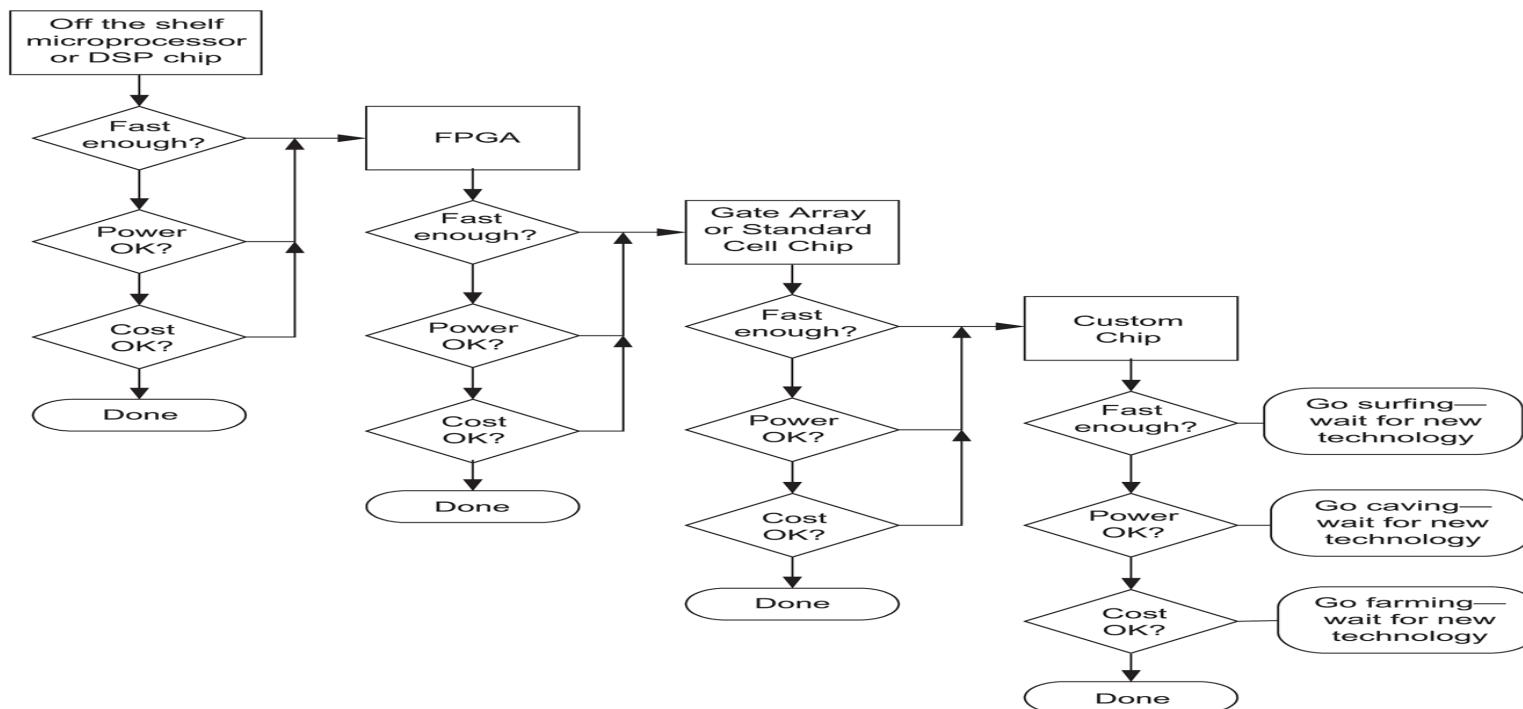


FIG 8.37 Design decision tradeoffs

# Design Flows

- ❑ A set of procedure to progress from a spec. to final chip implementation in an error-free way
- ❑ General flow

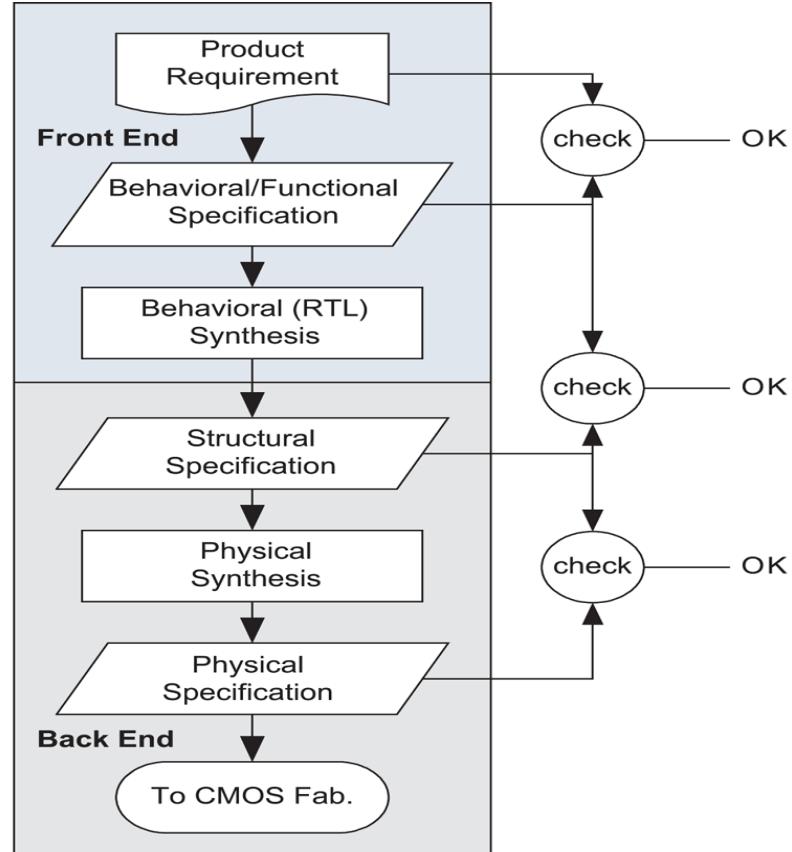


FIG 8.38 Generalized design flow

# Behavioral Synthesis Flow

## (ASIC Design Flow)

- From behavioral RTL description to a structural gate-level netlist

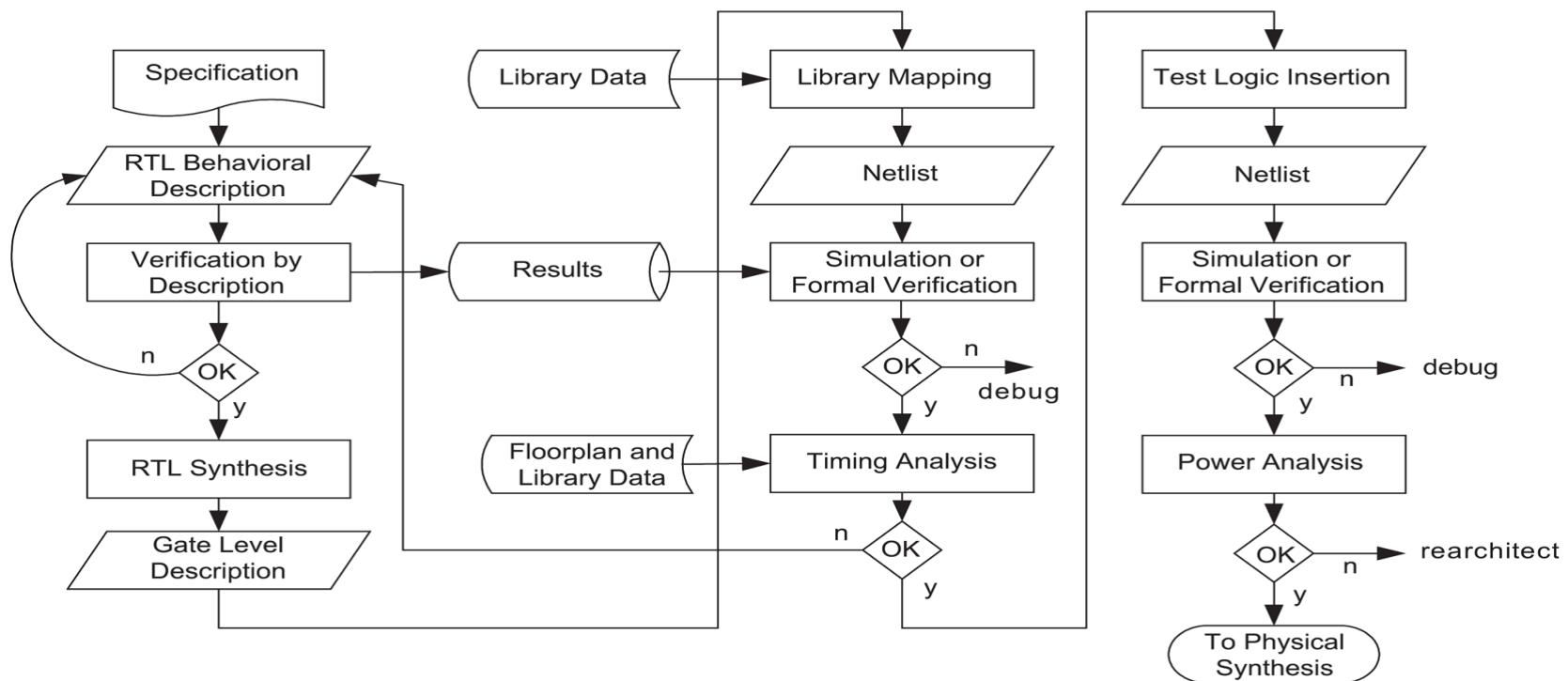


FIG 8.39 RTL synthesis flow

# Logic Design and Verification

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- RTL description in an HDL and a set of test benches
- Tools
  - Cadence: NC-verilog/SystemC/VHDL
  - Synopsys: VCS
  - Mentor Graphics: Modelsim
  - Aldec: ActiveHDL
- Hierarchical functional verification
  - usually from bottom up
- see behavioral Verilog code p 523

# Logic Design and Verification

```
module nco_struct(input      fclock, reset,
                  input [15:0] initial_phase, phase_increment,
                  output [7:0] q);

    wire [6:0] ROM_data;
    wire [15:0] phase_0;
    wire [5:0] nbus_5;
    wire [7:0] wave_out;
    wire [5:0] nbus_2;
    wire [15:0] nbus_1;
    wire [15:0] phase;

    xor i_7(wave_out[7], phase[15], 1'b0);
    xor i_6(wave_out[6], phase[15], ROM_data[6]);
    .
    .
    .
    xor i_2(wave_out[2], phase[15], ROM_data[2]);
    .
    .
    not i_10(nbus_5[2], phase[10]);
    not i_9(nbus_5[1], phase[9]);
    not i_8(nbus_5[0], phase[8]);
    generic_flip_flop phase_reg_15(.q(phase[15]), .d(phase_0[15]),
        .clk(fclock));
    .
    .
    .
    quarter_wave sine_table(.addr(the_address), .q(ROM_Table));
    .
endmodule
```

# RTL Synthesis

---

- Convert RTL to generic gate and registers, then optimize the logic
- Also do state machine decomposition, datapath optimization, and power optimization
- Commercial tools
  - Synopsys: Design Compiler (Vision)
  - Cadence: BuildGates
  - Synplicity: Synplify Pro
- see the synthesis code using the generic lib on p 524

# RTL Synthesis

```
module nco_struct(input      fclock, reset,
                   input [15:0] initial_phase, phase_increment,
                   output [7:0] q);

    wire [6:0] ROM_data;
    wire [15:0] phase_0;
    wire [5:0] nbus_5;
    wire [7:0] wave_out;
    wire [5:0] nbus_2;
    wire [15:0] nbus_1;
    wire [15:0] phase;

    xor i_7(wave_out[7], phase[15], 1'b0);
    xor i_6(wave_out[6], phase[15], ROM_data[6]);
    .
    .
    .
    xor i_2(wave_out[2], phase[15], ROM_data[2]);
    .
    .
    .
    not i_10(nbus_5[2], phase[10]);
    not i_9(nbus_5[1], phase[9]);
    not i_8(nbus_5[0], phase[8]);
    generic_flip_flop phase_req_15(.q(phase[15]), .d(phase_0[15]),
        .clk(fclock));
    .
    .
    .
    .
    quarter_wave sine_table(.addr(the_address), .q(ROM_Table));
    .
endmodule
```

# Library Mapping

---

- A generic HDL gate-level script to a netlist using particular gates in the target library
- see the library mapping result on p 524
  - Maps predefined blocks (memories) to their appropriate descriptions

# Library Mapping

```
module nco_struct_mapped(input      fclock, reset,
                           input [15:0] initial_phase, phase_increment,
                           output [7:0]  q);

    .
    .
    BUFX4 i_506(.A(n_355), .Y(q[7]));

    .
    .
    MX2X1 i_00(.S0(reset), .B(initial_phase[15]), .A(nbus_1[15]),
                .Y(phase_0[15]));
    NAND2BX1 i_8(.AN(n_102), .B(n_101), .Y(n_104));
    XOR2X1 i_6(.A(phase[15]), .B(ROM_Table[6]), .Y(n_103));
    .
    .
    DFFHQX1 phase_reg_0(.D(phase_0[15]), .CK(fclock), .Q(phase[15]));
    .
    .
    .
endmodule
```

# Functional or Formal Verification

---

- Check converted structural netlist = original behavioral HDL
- Verification strategies
  - 1. Rerun the logic test bench and compare both results
  - 2. Formal verification
    - Compare logical equivalence mathematically
    - Tools are still maturing
    - Commercial tools
      - Synopsys: Formality
      - Cadence: Conformal
  - 3. Semantic and structural check on the HDL, eg.
    - Semantic: ensure all bus assignments match in bit width
    - Structural: make sure all outputs are connected

# Static Timing Analysis

- ❑ Check the *temporal* requirement
- ❑ Timing analyzer using actual gate timing is too slow
- ❑ Static timing analysis
  - Use basic timing of library gates due to intrinsic gate delays and routing loads estimated from statistically or from floorplaning data
  - Runs quickly and exhaustively evaluates all timing paths
  - Check for both *max-delay* (for setup) and *min-delay* (for hold time)
  - Suffers from false path problems
    - Designer must manually flag such paths
  - Commercial tools
    - Cadence: Pearl
    - Synopsis: Pathmill and PrimeTime
- ❑ see the static timing analysis result on p 527
  - What's the slack time?

# Static Timing Analysis

```
Beginpoint: phase_reg_14/Q (^) triggered by leading edge of 'clock'  
Required Time 11.00  
- Arrival Time 5.89  
= Slack Time 5.11  
Clock Rise Edge 0.00  
+ Source Insertion Delay 0.20  
= Beginpoint Arrival Time 0.20  
+
```

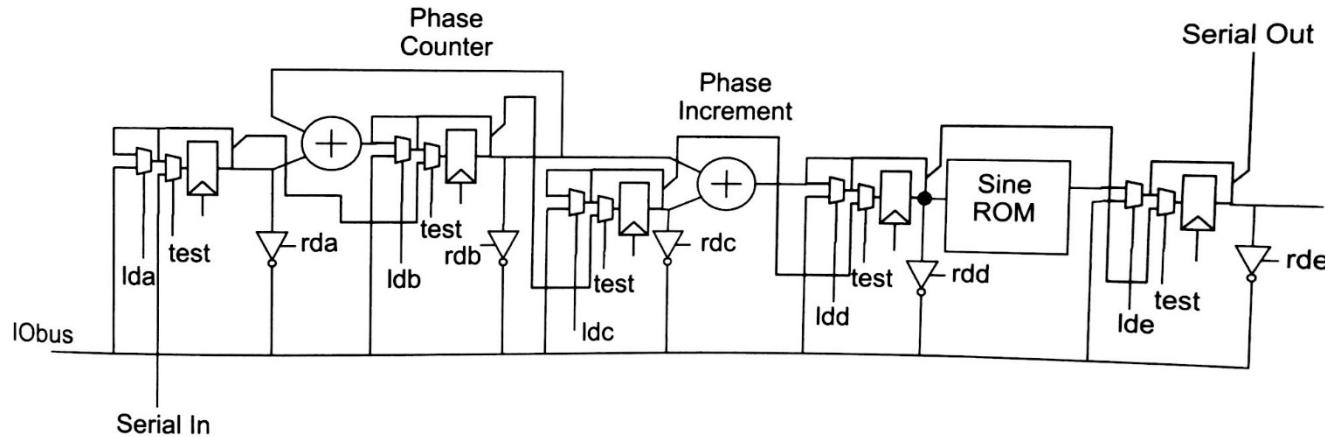
Instance	Arc	Cell	Delay	Arrival Time	Required Time
phase_reg_14	fclock ^ CK ^ -> Q ^	DFFHQX1	0.58	0.20 0.78	5.31 5.89
i_34	A ^ -> Y ^	XOR2X1	0.78	1.57	6.68
sine_table	addr[3] ^	quarter_wave		1.57	6.68
sine_table/i_371	A ^ -> Y v	INVX1	0.45	2.02	7.13
sine_table/i_42	B v -> Y ^	NOR2X1	0.19	2.21	7.32
sine_table/i_44	AN ^ -> Y ^	NAND2BX1	0.16	2.37	7.48
sine_table/i_145	A0 ^ -> Y v	AOI211X1	0.10	2.47	7.58
sine_table/i_6	C0 v -> Y ^	OAI211X1	0.13	2.61	7.72
sine_table/i_484	A ^ -> Y ^	BUFX4	0.96	3.57	8.68
sine_table	q[0] ^	quarter_wave		3.57	8.68
i_120	B ^ -> Y v	NOR2BX1	0.22	3.79	8.90
i_7	AN v -> Y v	NOR2BX1	0.20	3.99	9.10
i_9	AN v -> Y v	NOR2BX1	0.21	4.20	9.31
i_20	B v -> Y ^	NAND2BX1	0.12	4.32	9.43
i_3	AN ^ -> Y ^	NAND2BX1	0.17	4.49	9.60
i_8	AN ^ -> Y ^	NAND2BX1	0.19	4.67	9.78
i_31	A ^ -> Y ^	XNOR2X1	0.28	4.96	10.07
i_504	A ^ -> Y ^	BUFX4	0.93	5.89	11.00
	q[6] ^		0.00	5.89	11.00

# Test Insertion

---

- Insert scannable registers or optionally ATPG used to generate tests for a scannable design
- BIST to allow *in situ* testing
- Commercial tools
  - Synopsys: DFT complier
  - Tetramax: ATPG
  - LogicVision: Logic BIST and Memory BIST
- see the scan register insertion for testing on p 527

# Test Insertion



# Power Analysis

---

- Depends on the activity factors of the gates → depends on the inputs the chip receives
- Can be performed for a particular set of test vectors by running a simulator
  - Evaluate the total capacitance switched at each clock transition at each node
  - If too high, return to architectural level
- Commercial tools
  - Synopsys: PrimePower and Powermill

# Interchange Formats

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- Mostly text interchange formats
- GDS2 stream
  - *De facto* standard binary format for describing mask geometry
- Caltech Intermediate Format (CIF)
  - Alternative text-based mask description language (academic use)
- Library Exchange Format (LEF)
  - Describe the physical attributes of library cells
  - Abstract the lower-level geometric details of a cell
  - See the example on p 559

# Interchange Formats

```
LAYER metall
    TYPE ROUTING ;
    WIDTH 0.2 ;
    SPACING 0.4 ;
    PITCH 1.0 ;
    DIRECTION HORIZONTAL ;
    CAPACITANCE CPERSQDIST 0.00003 ;
END metal 1
...
MACRO adc
    ORIGIN 0 0 ;
    SIZE 100 BY 200 ;
    PIN in
    DIRECTION INPUT ;
    PORT
    LAYER METAL4 ;
    RECT 10 10 10.5 10.5
    END in
    ...
    OBS
    LAYER METAL1 ;
    RECT 0 100 20 150 ;
    END
END adc
```

# Interchange Formats

- Design Exchange Format (DEF)
  - Describe an actual design by listing the library elements and their placement and connectivity
  - See the example on p 560
- Standard Delay Format (SDF)
  - IEEE standard (P1497) to describe timing information
  - Specify pin-to-pin delays of modules, clock-to-data delays, and interconnect delays
  - See the example on p 560
  - INTERCONNECT clk\_pad (0.1:0.2:0.3) (0.4:0.5:0.6)
    - Rising and falling delays, (slow:normal:fast) process corners
- Detailed Standard Parasitic Format (DSPF) and Standard Parasitic Exchange Format (SPEF)
  - Use to pass parasitic RC values between extraction tools and timing verification tools
  - See the example on p 561

# Interchange Formats

## ✓ DEF

```
VERSION 5.2 ;
NAMESCASESENSITIVE ON ;
DIVIDERCHAR "/" ;
BUSBITCHARS "[]" ;
DESIGN chip ;
UNITS DISTANCE MICRONS 1000 ;

COMPONENTS 1 ;
-adc_inst adc + FIXED ( -1000 -1000 ) N ;
END COMPONENTS

END DESIGN
```

## ✓ SDEF

```
(DELAYFILE
(SDFVERSION "2.1")
(DESIGN "chip")
(DATE "March 24, 2003 11:57:3")
(VENDOR "")
(PROGRAM "PEARL")
(VERSION "PEARL 5.1-s072 (64 bit)")
(DIVIDER /)
(VOLTAGE 1.080:1.20:1.320)
(PROCESS "slow=1.5:nom=1.0:fast=0.75")
(TEMPERATURE 80.000:25.000:-40.000)
(TIMESCALE 1ns)
(CELL
(CELLTYPE "chip")
(INSTANCE)
(DELAY
(ABSOLUTE
(INTERCONNECT clk_mdi u_pad_clk_mdi/PAD (0.1:0.2:0.3) (0.4:0.5:0.6))
(INTERCONNECT u_pad_clk_mdi/PAD clk_mdi (0.4:0.5:0.6) (0.7:0.8:0.9))
)
)
(CELL
(CELLTYPE "DFlipFlop")
(INSTANCE foo/bar/reg)
(DELAY
(ABSOLUTE
(IOPATH CK Q (.2:.25:.3) (.3:.35:.4))
)
)
(TIMINGCHECK
(WIDTH (posedge CK) (.06:.06:.06))
(WIDTH (negedge CK) (.12:.12:.12))
(SETUP (posedge D) (posedge CK) (0.1:0.1:0.1))
)
)
)
)
)
```

# Interchange Formats

## ✓ SPEF

```
*|DSPF 1.5
*|DESIGN "chip"
*|DATE "Mon Mar 24 07:26:34 2003"
*|VENDOR "Cadence Design Systems - HLD"
*|PROGRAM "hyperExtract 4.5.0"
*|VERSION "3.4E"
*|DIVIDER |
*|DELIMITER .
*|BUSBIT []

.SUBCKT chip in out
+ Vdd gnd

*Net Section
*
*|GROUND_NET gnd
*
*|NET name1 0.003PF
*I ???
*S ???
C1 node1 node2 1.2
C2 node3 node4 0.85
R1 node4 node5 0.5
*
.ENDS
```

# Interchange Formats

---

- Advanced Library Format (ALF)
  - An alternate format used to describe primitive library elements
- WAVES Waveform and Vector Exchange Specification
  - WAVES: IEEE Std. 1029.1 and subset of the VHDL standard
  - Provides for the graphical definition of stimulus and response patterns
  - See the example on p 562
- Physical Design Exchange Format (PDEF)
  - Synopsys format to pass information between front-end and back-end tools
- **OpenAccess**
  - Provides API or set of software routines that communicate with a central database and extract data and insert data into that database
  - OpenAccess API for LEF and DEF descriptions

# Interchange Formats

```
% ****
% * This file is automatically generated WAVES vector file, *
% * and can be used in Test Bench generator. *
% * ACTIVE-HDL Testbench Generator ver. 3.5. *
% * Copyright (C) ALDEC Inc. *
% *
% * This file was generated on: 10:29:49 AM 12/9/2003 *
% ****
%
% Begin Comment
%
% reset : sig reg
% clk : sig reg
%
% 4.00 us : END_SIMULATION_TIME
% End Comment
%
% Begin of Vectors
%
%@ 0 0
x 0 : 15 ns ; % 0 fs
x 1 : 15 ns ; % 15 ns
1 0 : 15 ns ; % 30 ns
1 1 : 15 ns ; % 45 ns
.
1 0 : 15 ns ; % 330 ns
1 1 : 15 ns ; % 345 ns
1 0 : 15 ns ; % 360 ns
1 1 : 15 ns ; % 375 ns
0 0 : 15 ns ; % 390 ns
0 1 : 15 ns ; % 405 ns
0 0 : 15 ns ; % 420 ns
0 1 : 15 ns ; % 435 ns
0 0 : 15 ns ; % 450 ns
0 1 : 15 ns ; % 465 ns
```

# Automatic Layout Generation

---

- **Why we need automatic?**

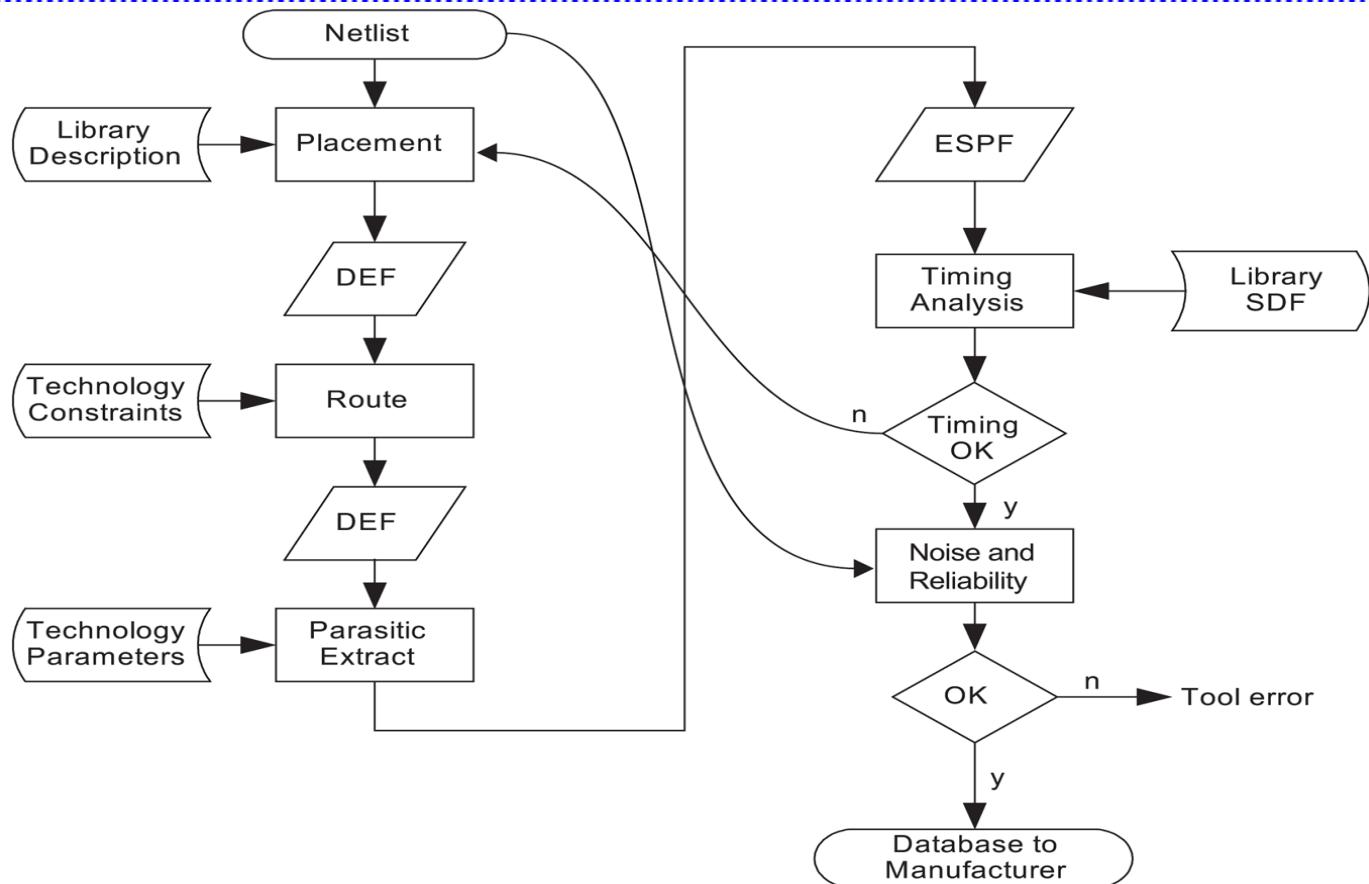
- For high productivity for most large digital chips with moderate performance (ASICs)
- For high end ICs like Intel CPUs → need custom design

- **Physical synthesis when the structural netlist is converted to physical layout**

- **Two methods**

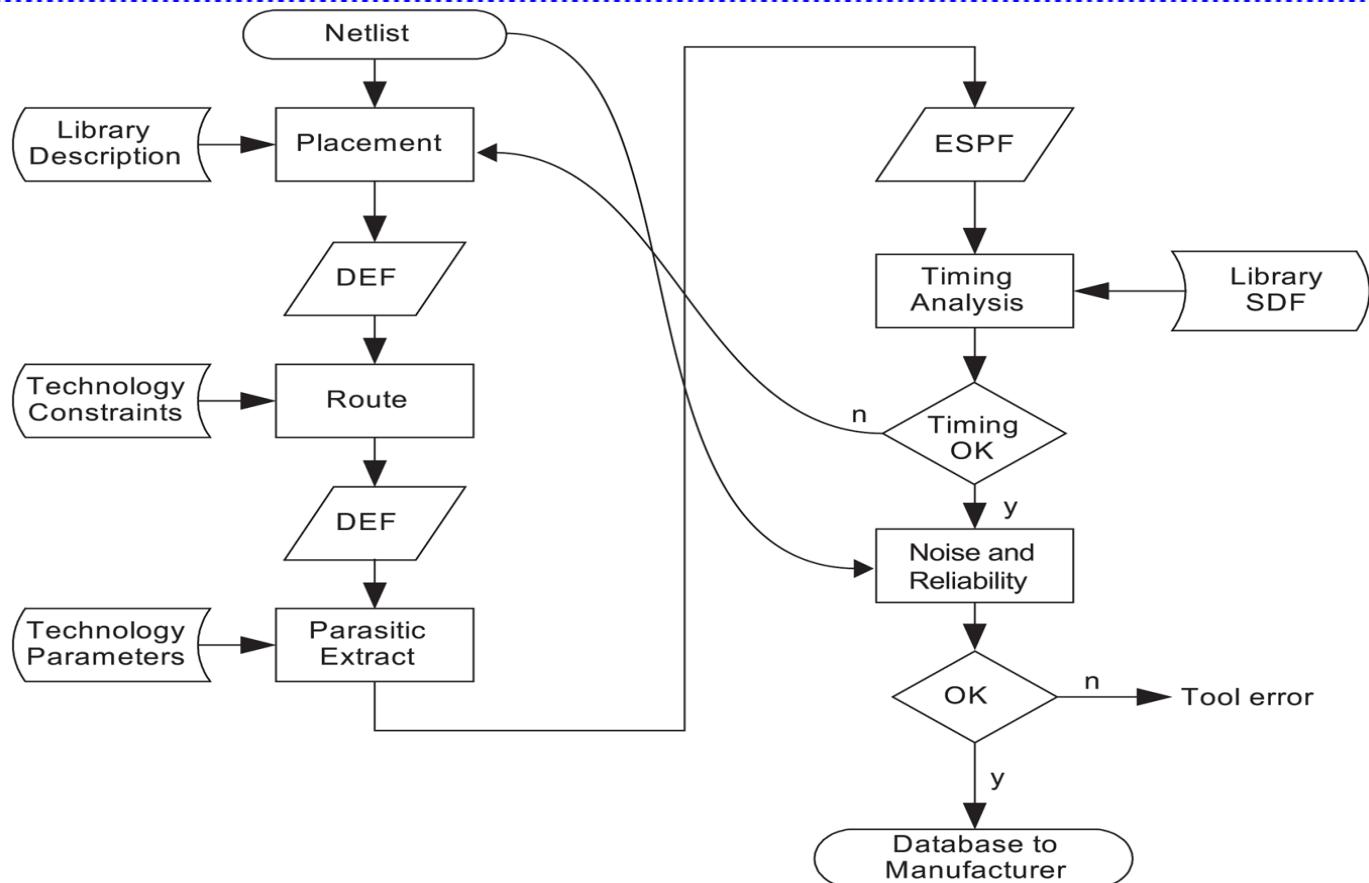
- Software generator (see sec. 8.3.5)
- Standard cell place and route (used on most ASICs) ← focused here

# Standard cell P&R flow



**FIG 8.41** Standard cell place and route design flow

# Standard cell P&R flow



**FIG 8.41** Standard cell place and route design flow

# Placement

- Constant height and variable-width cells
- Can add application specific custom block: memory, RF,..
  - “flow” around
- No separation between stand cell rows
  - Routing over the cells
- Floorplanning
  - Hierarchical manual floorplanning to increase locality before placement (optional)
  - See sec. 8.2.5

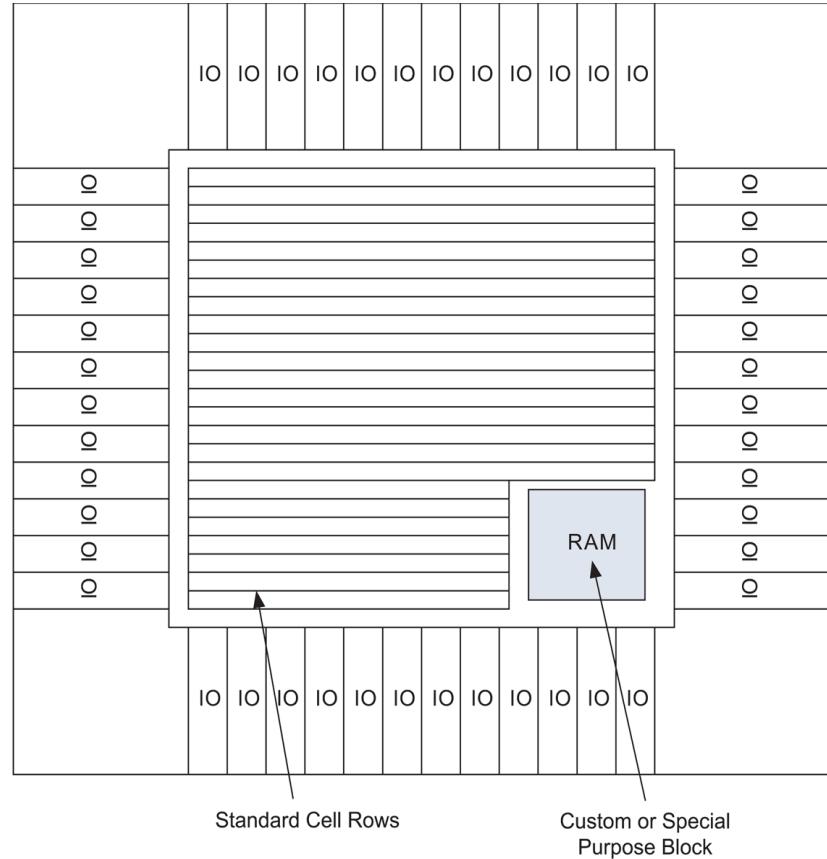


FIG 8.42 Standard cell chip layout

# Routing

---

- Two steps: global routing and detailed routing
- Global routing
  - Abstract the routing problem to a notional set of abutting channels
- Detailed routing
  - Add wires to channels to complete signal connections

# Parasitic Extraction

---

- Extract the parasitic RC associated with all nets in the layout after P&R
- 2D, 2.5D, 3D extractor

# Timing Analysis

---

- Rerun static timing analysis with actual routing loads placed on the gates
  - Bottleneck!!
- Usually multiple iteration of P&R to meet timing requirement
- If possible, a transistor-level timing simulation should be run
  - Somewhat reduced transistor modeling accuracy
  - Almost SPICE accuracy
- Commercial tools
  - Synopsys: Pathmill and Nanosim
  - Cadence: UltraSim

# **Noise, VDD and Electromigration Analysis**

---

- Noise analysis to evaluate crosstalk due to interlayer routing capacitance
- Commercial tools
  - Cadence: SignalStorm, ElectronStorm, and VoltageStorm

# Timing-driven Placement

- After the layout is completed, and extracting parasitic capacitance, if timing problem is found, we have to placement again → out of control for other complex parts in the chip!!
- The solution: timing-driven placement
  - Takes into account the timing of the circuits as cells are placed
  - Cells on critical paths are given priority to minimize the wire delay

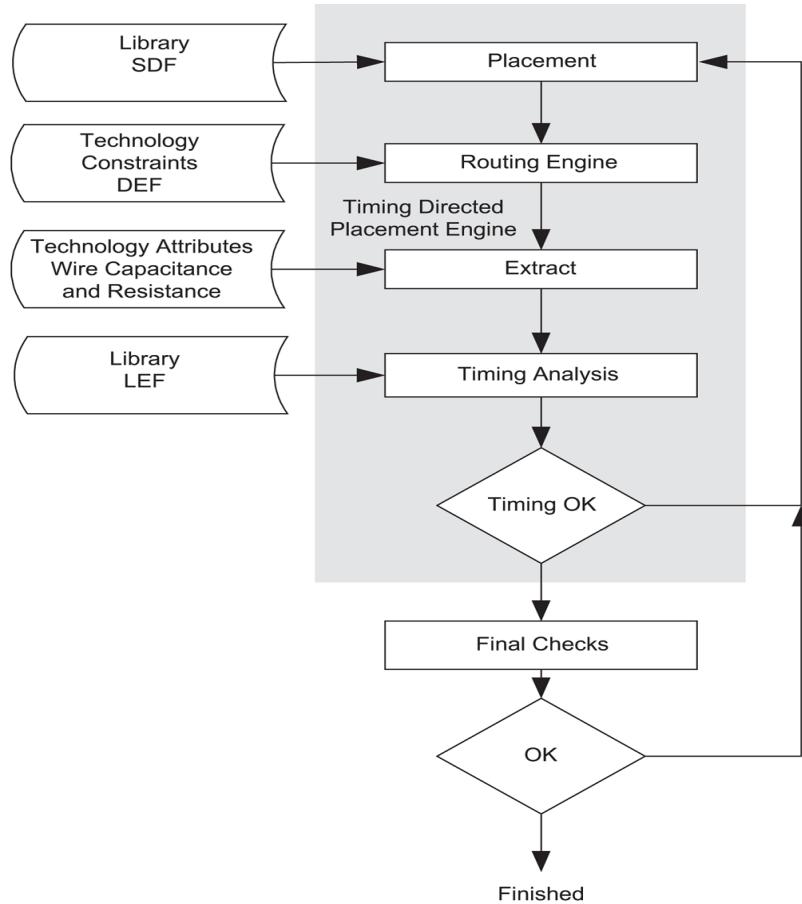


FIG 8.43 Timing directed placement design flow

# Clock-tree Routing

---

- To minimize skew, it is often best to route the clock and its buffers before the main logic placement and routing are completed
- Many approaches to the clock distribution strategies

# Power Analysis

---

- Now, real wire capacitances are available, and the power estimation can be repeated
- Similar techniques to those used during RTL synthesis are used

# Mixed-signal or Custom-design Flow

- For small analog, RF, and high-speed digital IC designs, we use a custom-design flow

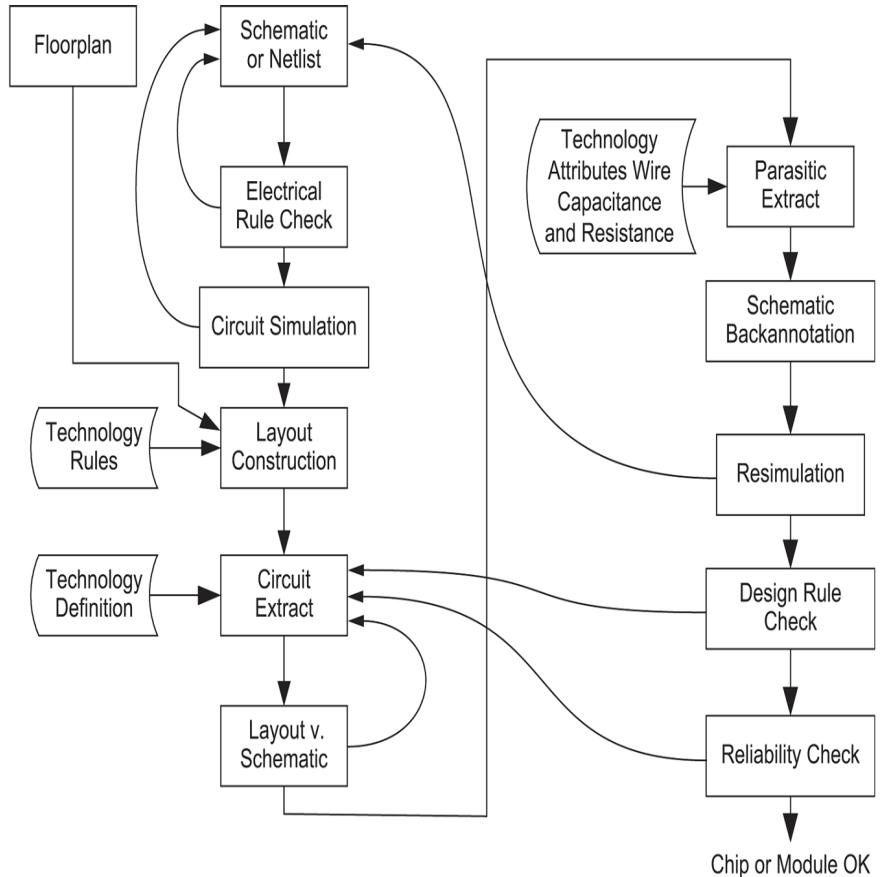


FIG 8.44 Mixed-signal or custom-design flow

# Data Sheets and Documentation

---

- Describe what it does and outlines the specs for making the IC work in a system**
- Summary**
  - Designation and descriptive name of the chip
  - Concise description of what the chip does
  - A feature list
  - High-level block diagram of the chip function
- Pinout**
  - Name of the pin, type of the pin, brief description of the pin function, and the package pin number
- Description of Operation**

# Data Sheets and Documentation

---

- **DC Specs**
  - Supply voltage, pin voltages, junction temperature,
  - $V_{IL}$  and  $V_{IH}$ ,  $V_{OL}$  and  $V_{IH}$
  - Input loading for each input
  - Quiescent current, leakage current,...
- **AC specs**
  - Setup and hold times on all input
  - Clock to output delay times
  - Other critical timing such as minimum pulse widths
- **Package diagram**
- **Principles of operational manual**
- **User manual**

# Closing the Gap between ASIC and Custom

- **High speed uPs and DSP**
  - Custom design with which designers use a wide variety of circuit techniques and carefully tune all the critical parts of the chip
- **ASICs**
  - Built by automatic HDL synthesis and layout using a standard cell library
- **Performance gap of 180nm process**
  - Ups: 1-2 GHz
  - ASIC: 200-350 MHz
- **Overall, custom design = 3-8x frequency advantage over ASICs**
- **Delays**
  - ASICs: 50-100 FO4
  - Pentium II and III: 20-24 FO4
  - Pentium 4: 10 FO4
- **See table 8.5 p 548**

# Closing the Gap between ASIC and Custom

**Table 8.5** Relative performance of custom vs. ASIC design methodologies

Factor	vs. Poor ASIC	vs. Best Practice ASIC
Microarchitecture (e.g., pipelining)	1.8x	1.3x
Sequencing overhead: elements, skew, time borrowing	1.45x	1.1x
Circuit families (e.g., domino)	1.4x	1.2x
Logic design	1.3x	1.0x
Cell design, cell sizing, and wire sizing	1.45x	1.1x
Layout: floorplanning, placement, wire management	1.4x	1.0x
Exploiting process variation and accessibility	2x	1.2x



# What are the factors?

---

- Microarchitecture
  - Pipelining or performing multiple operations simultaneously
  - ASICs: greater sequencing overhead
    - Most ASICs use very conservative FFs: 4-6 FO4 delay
    - Cannot benefit from pipelining
- Sequencing overhead
  - uPs: use more aggressive sequential circuits such as latches, 2-3 FO4 delay
    - Better for clock skew tolerance
- Circuit families
  - Most custom designs use skew-tolerant domino circuits on critical paths
    - 1.5-2x faster than CMOS

# What are the factors?

---

- Logic design
  - Custom: optimized logic design, eg., lookahead adder not ripple carry adders and Booth-encoded multipliers
  - ASICs: synthesized from HDL → older tools: should specify manually Booth multipliers
- Cell and Wire design
  - ASICs: use a standard library. some library has a small selection of gates. → may be 25% slower than a rich selection!!
  - Custom: unlimited set of cell sizes
  - ASIC designer have little control over the wire selection
- Layout

# What are the factors?

- Process variation
  - ASICs: designed for the SS process corner so that all of the chips will meet timing
    - long tail at the slow end
  - Custom: designed for the TT process
    - 17%-28% speedup at the expense of rejecting a few chips
    - Fastest 10% of the chips may be up to 30% faster than TT
    - UPS are commonly shorted by speed, and the fastest ones are sold at a premium ← *binning*

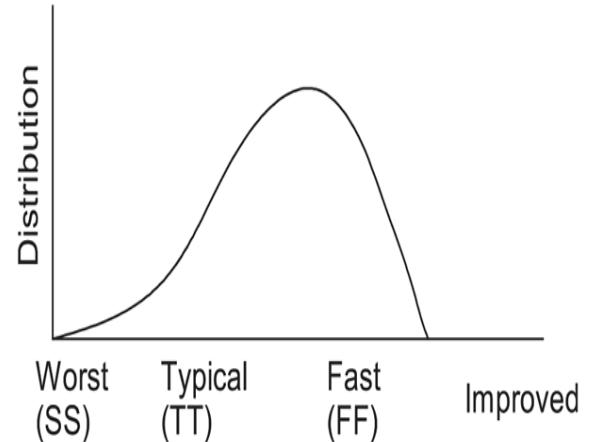


FIG 8.48 Distribution of chip behavior